





Substitute Form PTO-1449 (Modified)

U.S. Department of Commerce Patent and Trademark Office

Inf rmation Discl sure Statement

by Applicant (Use several sheets if necessary)

Attorney's Docket No. 07977/252001

Application No. 09/198,073

Applicant

Shunpei Yamazaki, et al.

Filing Date

Group Art Unit

Substitute Disclosure Form (PTO-1449)

(37 CFR §1.98(b))

November 23, 1998

2871

			U.S. Pate	ent Documents	_		
Examiner Initial	Desig.	Patent Number	Issue Date	Patentee	Class	Subclass	Filing Date If Appropriate
-11	AA	5,148,301	9/15/92	Sawatsubashi et al.			
1	AB	5,261,156	11/16/93	Mase et al.		/ .	
	AC	5,654,811	8/5/97	Spitzer et al.		1	
i	AD	5,757,456	5/26/98	Yamazaki et al.			
	AE	5,766,977	6/16/98	Yamazaki	1		
	AF	5,781,164	7/14/98	Jacobsen et ai.	•		
	AG	5,834,327	11/10/98	Yamazaki et al.	,		
	АН			·			
	AI						
	AJ						
	AK						

·····	Foreign Patent Documents or Published Foreign Patent Applications								
Examiner Initial	Desig. ID	Document Number	Publication Date	Country or Patent Office	Class	Subclass	. Trans		
	AL								
	AM								
	AN						·		
	AO	·							
	AP								

Other Documents (include Author, Title, Date, and Place of Publication)						
Examiner Initial	Desig. ID	Document				
	AQ					
	AR					
	AS					
	AT					

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PTO-1449 U.S. Department of Commerce Patent and Trademark Office	Attorney's Docket No. 07977/252001	Application No. 09/198,073	3 PTO	
/ - J. T. F.	Applicant Shunpei Yamazaki, et al.		U.S. 11692	
(Use several sheets if necessary) (37 CFR §1.98(b))	Filing Date November 23, 1998	Group Art Unit 2871	1011	

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Examiner Initial	Desig. ID	Patent Number	Issue Date	Patentee	Class	Subclass	Filing Date If Appropriate	
11	AA	5,261,156	11/16/93	Mase et al.				
7	AB	5,648,277	7/15/97	Zhang et al.				
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	Foreign Patent Documents or Published Foreign Patent Applications							
Examiner Initial	Desig. ID	Document Number	Publication Date	Country or Patent Office	Class	Subclass	Tran:	slation
11	AL	JP 08-078329	3/22/96	Japan			X	
1	AM	JP 10-135468	5/22/98	Japan			x	
	AN	JP 10-247735	9/14/98	Japan			X	
	AO	JP 07-135318	5/23/95	Japan			x	
	AP	JP 07-014880	1/17/95	Japan			х	

	Other Do	ocuments (include Author, Title, Date, and Place of Publication)
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